Lecture 07: 3-D Nanostructures Fabrication

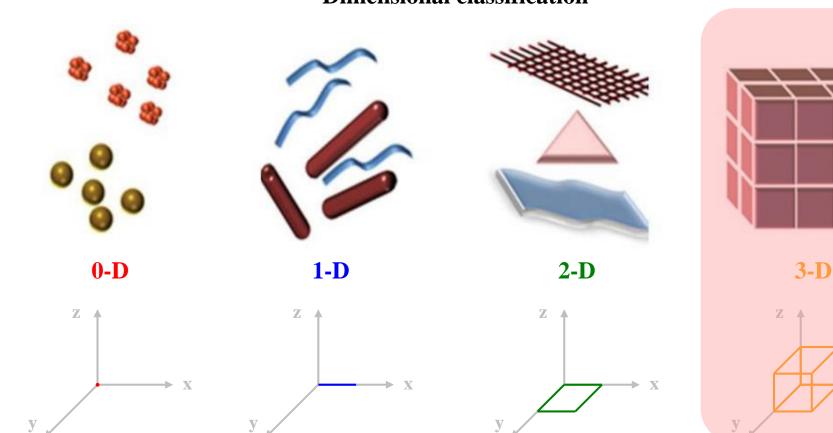
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Introduction to 3-D nanostructures fabrication

Classification of nanomaterials

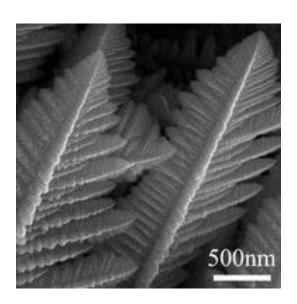
Dimensional classification



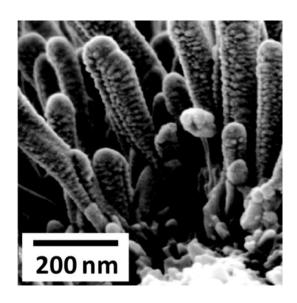
Classification of nanomaterials

Three-dimensional (3-D) structures

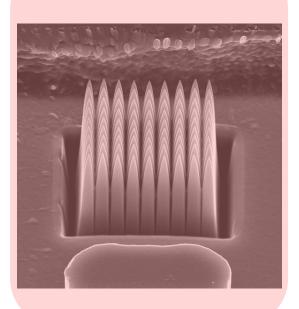
- Dendrite -



- Nanostructured thin film -



- Nanopattering -



Photolithography

Lithography

Lithography process



Lithographic pencil applied



Bitumen applied to surface



Greasy ink rolled on



Paper over inked surface



Final result

Photolithography

Photolithography Process



Silicon wafer

We begin with a clean

silicon wafer spincoated

with photoresist







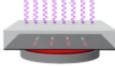
Photomask

A glass or mylar mask

coated with an opaque

film defines the features





Exposure

A mask aligner is used to

pass UV light through the

mask onto the wafer





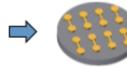


Exposed resist is washed away while unexposed resist remains





Metallic, semiconducting or insulating layers are evaporated or sputtered onto the surface



Liftoff

Photoresist is removed, leaving behind precisely deposited features









Wet or Dry Etch

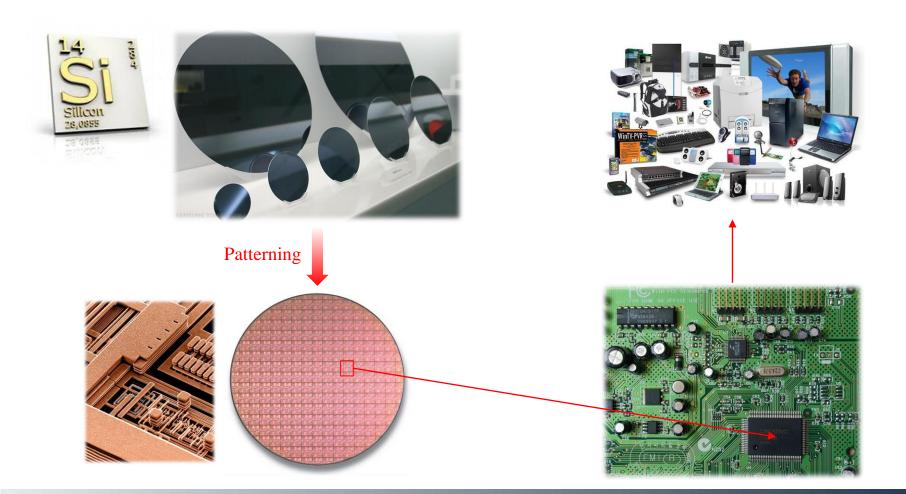
Exposed sections are etched away while the resist protects the remaining areas

Resist removal

Photoresist is removed, leaving behind precisely etched features

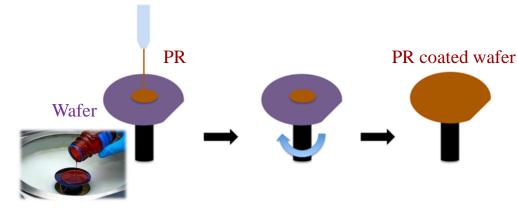


Photolithography: substrate (silicon wafer)



Photolithography: photoresist (PR)

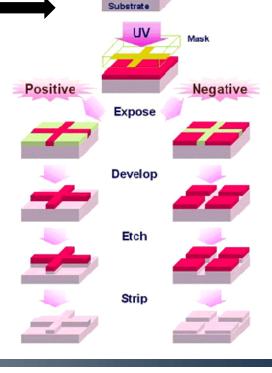
PR spin coating



Positive PR vs. Negative PR

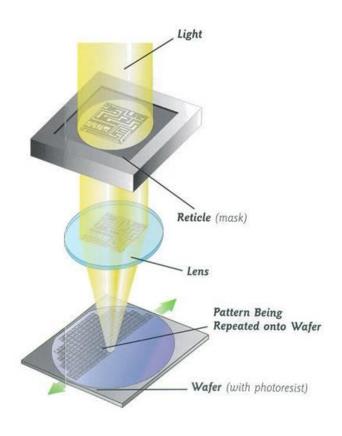
Positive PR: Exposure to the UV light changes the chemical structure of the resist so that it becomes more soluble in the develop solution.

Negative PR: Exposure to the UV light causes the negative resist to become more difficult to be dissolved, meaning that the develop solution removes only the unexposed parts.



Photoresist

Photolithography: exposure



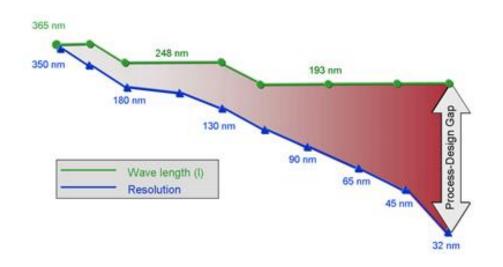
Resolution:

$$R = K \times \frac{\lambda}{n \sin \theta}$$

K: technical limited constant

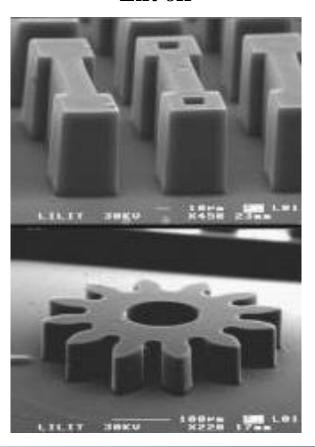
 λ : wavelength (UV: 100 ~ 400 nm)

n: an index of refraction (air = 1)

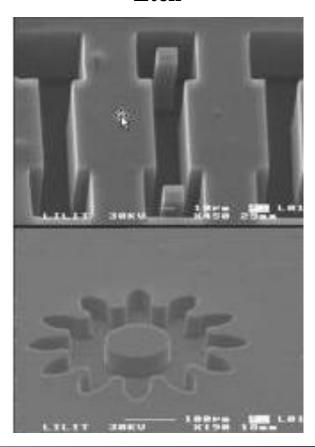


Photolithography: lift off vs. etch

Lift off

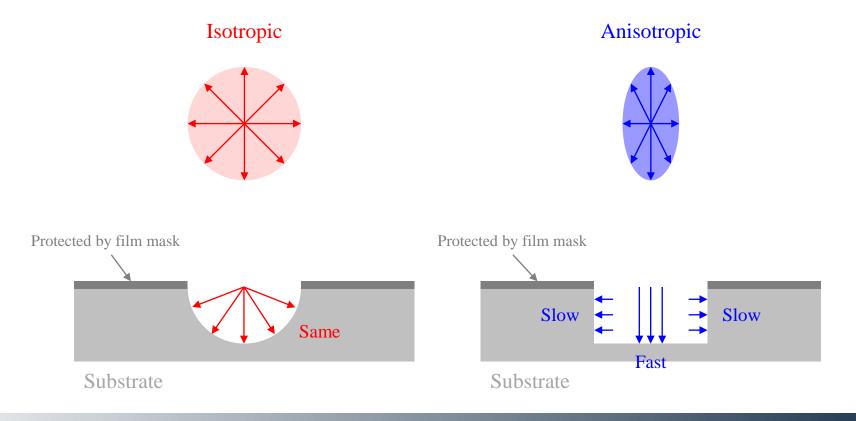


Etch



Etch: isotropic vs. anisotropic

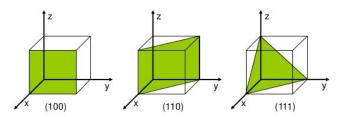
Etch is the process of using strong acid or base to cut into the unprotected parts of a surface to create a design.



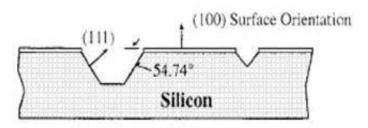
Anisotropic etch: Si orientation

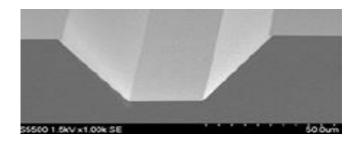
Si (111) shows an extremely low etch rate in KOH solution.

KOH etch on Si: $Si + 2OH^{-} + 2H_{2}O \rightarrow [SiO_{2}(OH)_{2}]^{2-} + 2H_{2}$

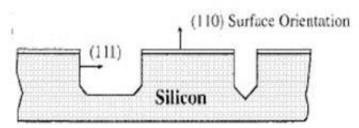


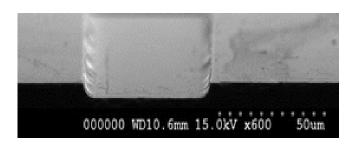
Si (100) anisotropic wet etch



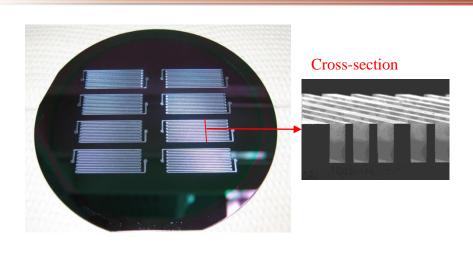


Si (110) anisotropic wet etch





Photolithography: rectangular channels



Substrate: Si wafer (110) Thickness: 500 µm

 $\frac{SiO_2 \ formation}{ thickness: 1 \ \mu m)}$ Thermal oxide was grown onto Si (110) wafer by thermal wet oxidation.

Photoresist (PR) coating AZ1512, thickness: 1 μm

Film mask Channel width: 600 μm

Exposure

UV, exposure energy: 15 mW \times 4.5 sec

Development AZ 300 developer

 $\pmb{\text{Buffered HF (BHF) etching}}$

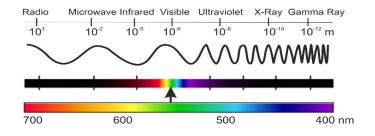
 $NH_4F : HF = 7 : 1$

PR strip $H_2SO_4: H_2O_2 = 4:1$

KOH wet etching 30 wt% KOH solution, at 80 for 3 hrs

> Buffered HF (BHF) etching NH₄F: HF = 7:1

Lithography techniques



Resolution:

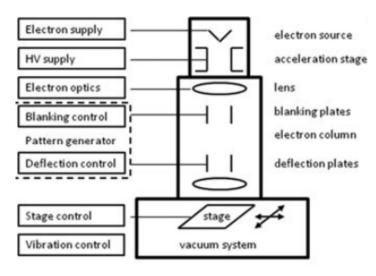
$$R = K \times \frac{\lambda}{n \sin \theta}$$

K: technical limited constant

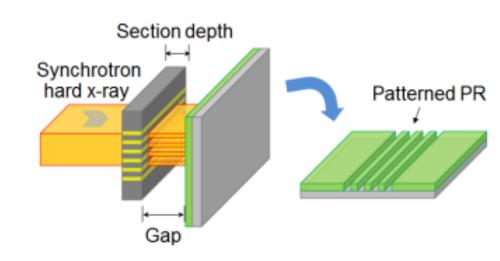
λ: wavelength

n: an index of refraction

Electron-beam lithography



X-ray lithography



Lithography techniques

Comparison

Photolithography

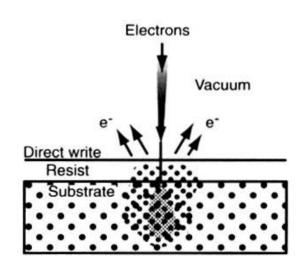
Visible Photons

Air

Contact mask
Resist
Substrate

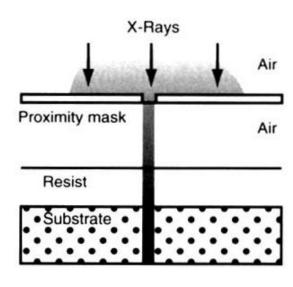
diffraction limits resolution

Electron-beam lithography



Scattering problem

X-ray lithography



Little diffraction, high depth of focus

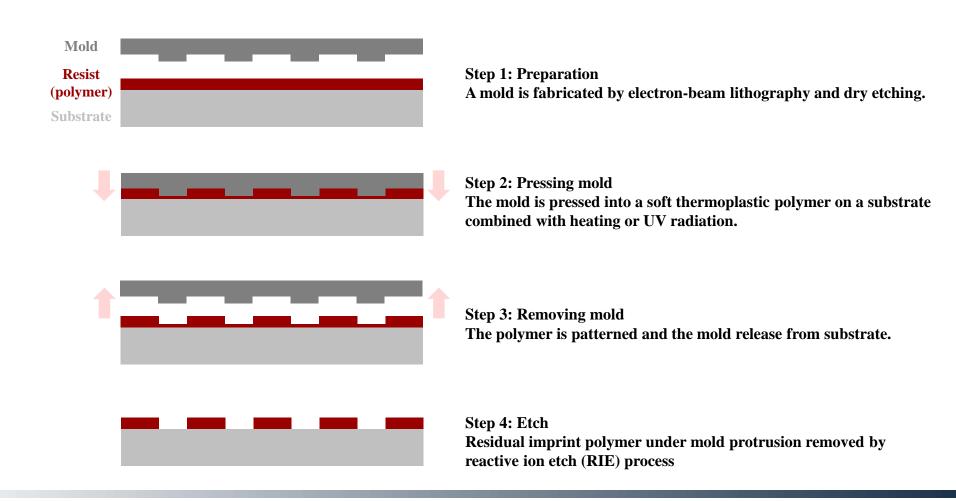
Lithography techniques

Comparison

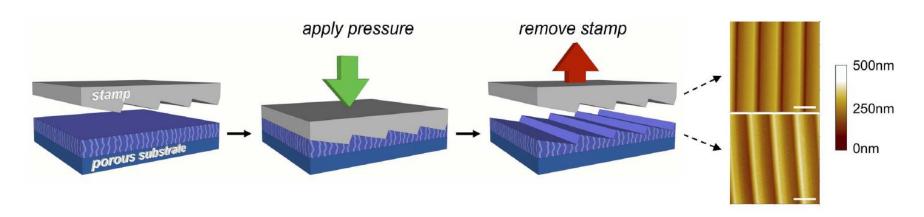
	Photolithography	Electron-beam lithography	X-ray lithography
Source	Ultraviolet (UV)	Electron	X-ray
Wavelength	100 ~ 400 nm	Depending on voltage	0.4 ~ 4 nm
Resolution limit	~ 125 nm	~ 20 nm	~ 15 nm
Resist	Various polymers	Polymethylmethacrylate	Polymethylmethacrylate
Advantages	Fast process Simple Relatively low cost	Print complex patterns directly on wafers Eliminates the diffraction problem Flexible technique	Utilizes short wavelength of 1 nm Simple: Requires no lenses Allows for small feature size Faster than electron-beam lithography
Disadvantages	Low resolution	Slower than photolithography Expensive and complicated Secondary electrons	Thin lens Cannot be focused through lens Masks are expensive to produce

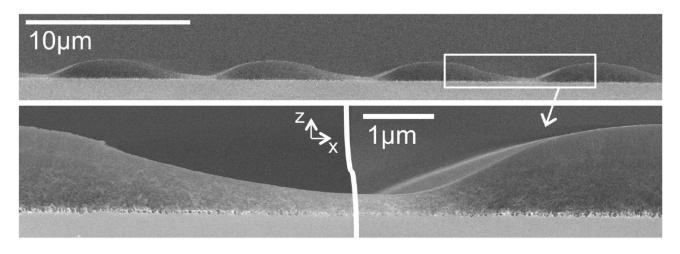
Nanoimprint lithography

Nanoimprint lithography: process

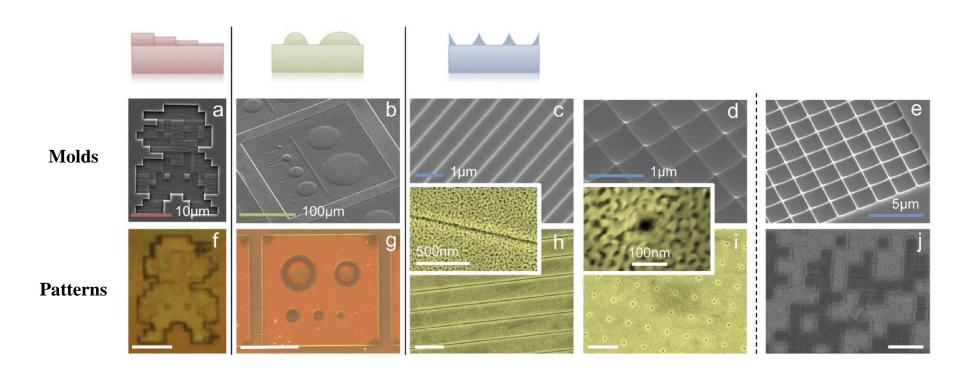


Nanoimprint lithography: process



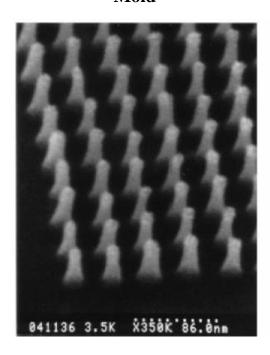


Nanoimprint lithography: examples



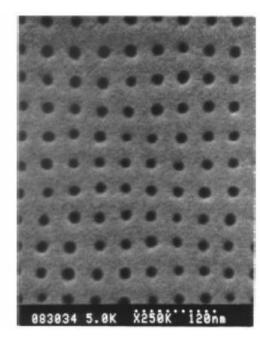
Nanoimprint lithography: examples

Mold



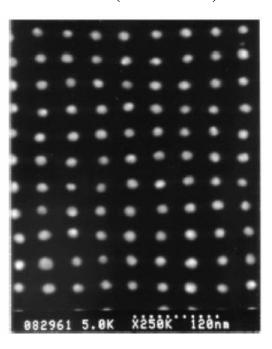
10 nm diameter pillar mold

Resist (after pressing mold)



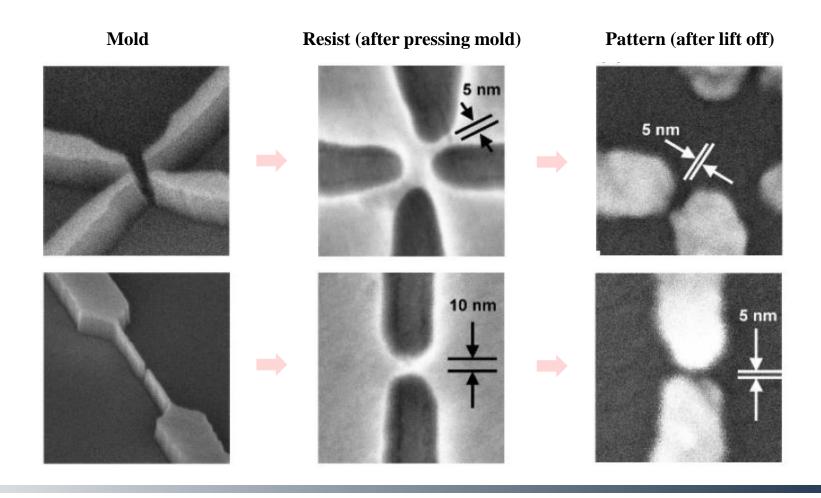
10 nm diameter resist holes by imprinting

Pattern (after lift off)



10 nm diameter metal dots by imprint and lift off

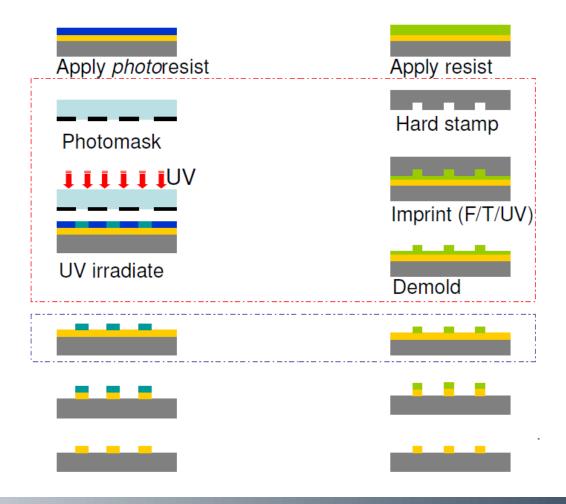
Nanoimprint lithography: examples



Nanoimprint lithography: comparison

Photo lithography

Resolution limit ~ 125 nm

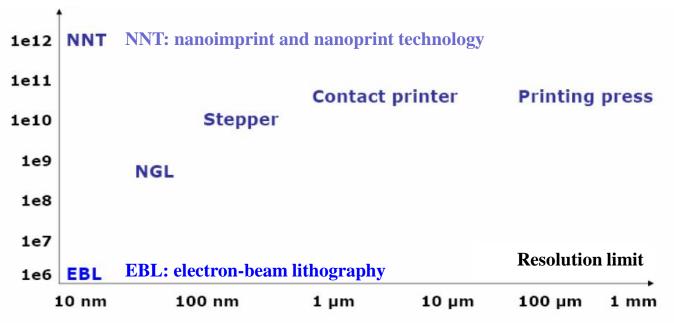


Nanoimprint lithography

Resolution limit $5 \sim 50 \text{ nm}$

Nanoimprint lithography: comparison

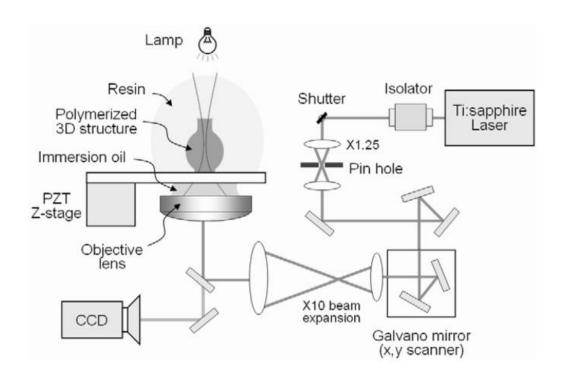
Manufacturing speed / s

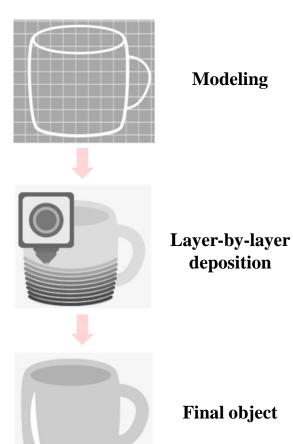


Nanoimprint lithography has an advantages for mass production of nano patterns.

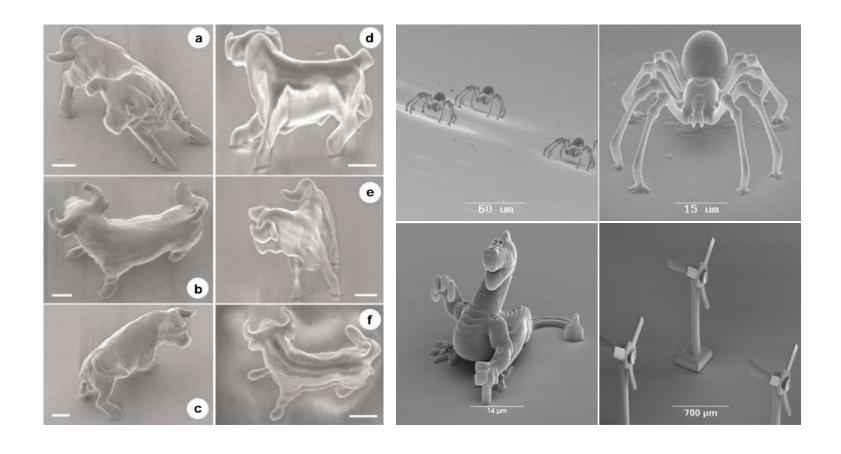
Nano-stereolithography

Nano-stereolithography





Nano-stereolithography: examples



Nano-stereolithography: examples

